Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/541,237	FUJITA ET AL.		
Examiner	Art Unit		
Jean F. Duverne	2839		

SEARCHED					
Class	Subclass	Date	Examiner		
439	630	10/1/2006	JFD		
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	593	10/1/2006	JFD		
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INTERFERENCE SEARCHED

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